

<b>Notice of References Cited</b>	Application/Control No. 10/026,618	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Emmanuel Bayard	Art Unit 2611	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,805,017	09-1998	Razzell, Charles J.H.	329/300
*	C	US-2002/0090923	07-2002	Muramoto, Kimio	455/192.2
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*	E	US-6,925,108	08-2005	Miller et al.	375/150
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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